TOSHIBA Field Effect Transistor Silicon P Channel MOS Type (U-MOS III)

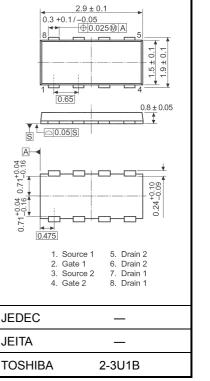
# **TPCF8301**

## Notebook PC Applications Portable Equipment Applications

- Low drain-source ON resistance:  $R_{DS}$  (ON) = 72 m $\Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 4.7 \text{ S} (typ.)$
- Low leakage current:  $I_{DSS} = -10 \ \mu A \ (max) \ (V_{DS} = -20 \ V)$
- Enhancement-model:  $V_{th} = -0.5$  to -1.2 V
  - $(V_{DS} = -10 \text{ V}, \text{ ID} = -200 \text{ }\mu\text{A})$

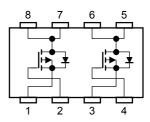
#### Maximum Ratings (Ta = 25°C)

Cha	Symbol Rating		Unit		
Drain-source voltage		V <sub>DSS</sub>	-20	V	
Drain-gate voltage ( $R_{GS} = 20 \text{ k}\Omega$ )		V <sub>DGR</sub>	-20	V	
Gate-source voltag	V <sub>GSS</sub>	±8	V		
Drain current	DC (Note 1)	I <sub>D</sub>	-2.7	А	
Drain current	Pulse (Note 1)	I <sub>DP</sub> –10.8 Р <sub>D (1)</sub> 1.35	7		
Drain power dissipation (t = 5 s) (Note 2a)	Single-device operation (Note 3a)	P <sub>D (1)</sub>	1.35	W	
	Single-device value at dual operation (Note 3b)	P <sub>D (2)</sub>	1.12		
Drain power dissipation (t = 5 s) (Note 2b)	Single-device operation (Note 3a)	P <sub>D (1)</sub>	0.53		
	Single-device value at dual operation (Note 3b)	P <sub>D (2)</sub>	0.33		
Single pulse avala	nche energy (Note 4)	E <sub>AS</sub>	1.2	mJ	
Avalanche current	Avalanche current		-1.35	А	
Repetitive avalanche energy Single-device value at dual operation (Note 2a, 3b, 5)		E <sub>AR</sub> 0.11		mJ	
Channel temperatu	ıre	T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55~150	°C	

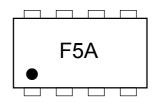


Weight: 0.011 g (typ.)

### **Circuit Configuration**



## Marking (Note 6)



# Thermal Characteristics

Characteristics		Symbol	Max	Unit	
Thermal resistance, channel to ambient (t = 5 s) (Note 2a)	Single-device operation (Note 3a)	R <sub>th (ch-a) (1)</sub>	92.6	°C/W	
	Single-device value at dual operation (Note 3b)	R <sub>th (ch-a) (2)</sub>			
Thermal resistance, channel to ambient	Single-device operation (Note 3a)	R <sub>th (ch-a) (1)</sub>	235.8	°C/W	
(t = 5 s) (Note 2b)	Single-device value at dual operation (Note 3b)	R <sub>th (ch-a) (2)</sub>	378.8		

Note: For (Note 1), (Note 2), (Note 3), (Note 4), (Note 5) and (Note 6), please refer to the next page.

This transistor is an electrostatic sensitive device. Please handle with caution.

Unit: mm

**Electrical Characteristics (Ta = 25°C)** 

Cha	aracteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I <sub>GSS</sub>	$V_{GS}=\pm 8~V,~V_{DS}=0~V$	_	_	±10	μA
Drain cut-off curr	ent	I <sub>DSS</sub>	$V_{DS} = -20 \text{ V}, V_{GS} = 0 \text{ V}$	_	_	-10	μA
Drain-source bre	akdown voltage	V (BR) DSS	$I_D = -10$ mA, $V_{GS} = 0$ V	-20		—	v
Drain-source breakdown voltage		V (BR) DSX	$I_D = -10$ mA, $V_{GS} = 8$ V	-12	_	—	v
Gate threshold ve	oltage	V <sub>th</sub>	$V_{DS} = -10 \ V, \ I_D = -200 \ \mu A$	-0.5		-1.2	V
		R <sub>DS (ON)</sub>	$V_{GS} = -1.8 \text{ V}, \ I_D = -0.7 \text{ A}$	_	215	300	
Drain-source ON resistance		R <sub>DS (ON)</sub>	$V_{GS} = -2.5 \text{ V}, \ I_D = -1.4 \text{ A}$	_	110	160	mΩ
		R <sub>DS (ON)</sub>	$V_{GS} = -4.5 \; V, \; I_D = -1.4 \; A$	_	72	110	
Forward transfer admittance		Y <sub>fs</sub>	$V_{DS} = -10 \text{ V}, \text{ I}_{D} = -1.4 \text{ A}$	2.4	4.7		S
Input capacitance		C <sub>iss</sub>		_	470	—	
Reverse transfer	capacitance	C <sub>rss</sub>	$V_{DS} = -10 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ f} = 1 \text{ MHz}$	_	70	_	pF
Output capacitance		C <sub>oss</sub>		_	80	_	
Switching time	Rise time	tr	$v_{DS} = -10 \text{ V}, v_{GS} = 0 \text{ V}, t = 1 \text{ MHz}$ $v_{GS} = 0 \text{ V}, t = 1 \text{ MHz}$ $v_{GS} = 0 \text{ V}, t = 1 \text{ MHz}$ $v_{GS} = 0 \text{ V}, t = 1 \text{ MHz}$		5	_	
	Turn-on time	t <sub>on</sub>		_	9	_	20
	Fall time	t <sub>f</sub>		_	8	_	ns
	Turn-off time	t <sub>off</sub>	$V_{DD} \simeq -10 \text{ V}$ Duty $\leq 1\%, t_W = 10 \ \mu \text{s}$		26		
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \simeq -16 \text{ V}, \text{ V}_{GS} = -5 \text{ V},$		6		
Gate-source charge		Q <sub>gs</sub>	$I_{\rm D} = -2.7 \rm{A}$	_	4	—	nC
Gate-drain ("miller") charge		Q <sub>gd</sub>		_	2	—	

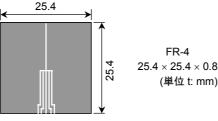
#### Source-Drain Ratings and Characteristics (Ta = 25°C)

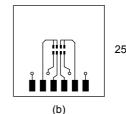
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I <sub>DRP</sub>	_	_	_	-10.8	А
Forward voltage (diode)		V <sub>DSF</sub>	$I_{DR} = -2.7 \text{ A}, V_{GS} = 0 \text{ V}$		_	1.2	V

Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2: (a) Device mounted on a glass-epoxy board (a) (b) Device mounted on a glass-epoxy board (b)

Note 3: a) The power dissipation and thermal resistance values are shown for a single device





FR-4 25.4 × 25.4 × 0.8 (単位: mm)

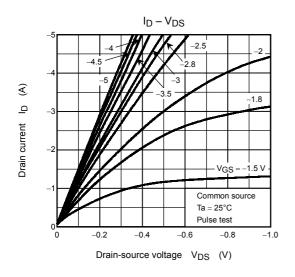
(a)

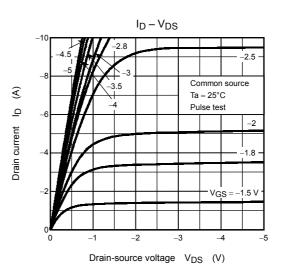
(During single-device operation, power is only applied to one device.).

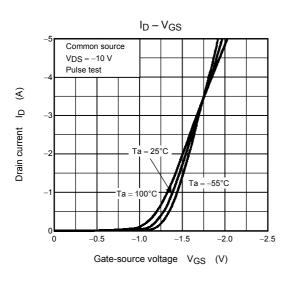
b) The power dissipation and thermal resistance values are shown for a single device (During dual operation, power is evenly applied to both devices.).

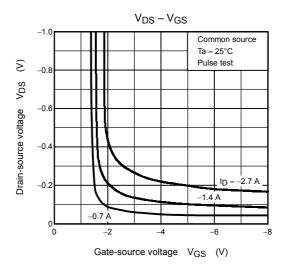
- Note 4:  $V_{DD} = -16 \text{ V}, \text{ T}_{ch} = 25^{\circ}\text{C}$  (initial), L = 0.5 mH, R<sub>G</sub> = 25  $\Omega$ , I<sub>AR</sub> = -1.35 A
- Note 5: Repetitive rating; Pulse width limited by Max. Channel temperature.
- Note 6: Black round marking "●" locates on the left lower side of parts number marking "F5A" indicates terminal No. 1.

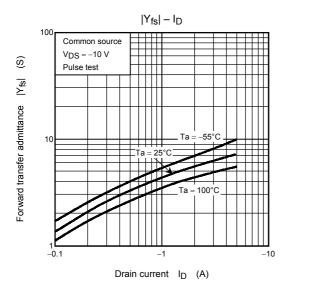
# **TOSHIBA**

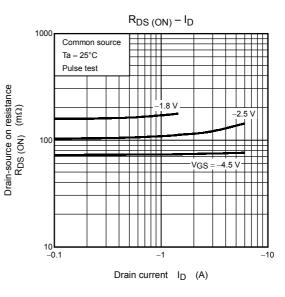


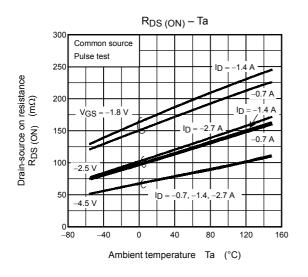


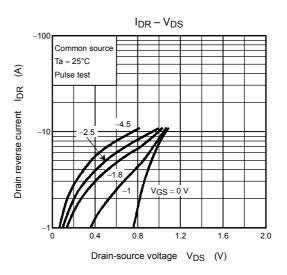


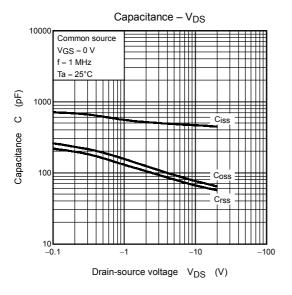


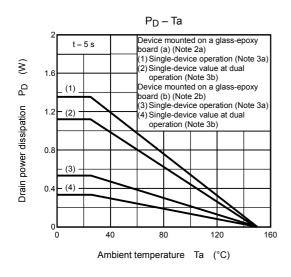


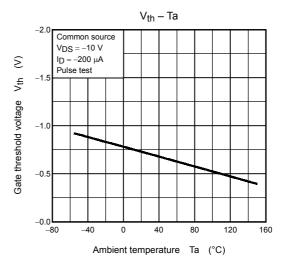


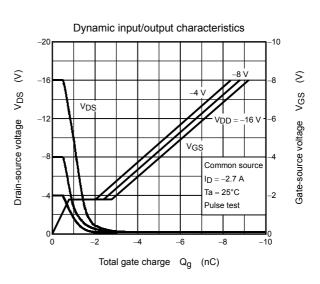


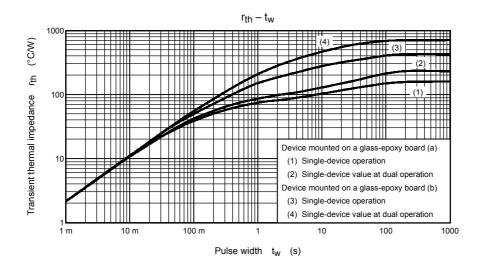


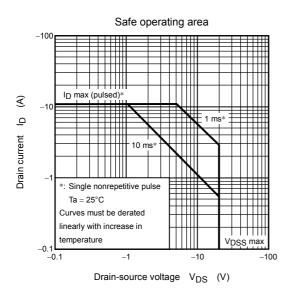












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